

INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application No.	10/815,905
		Filing Date	March 31, 2004
		First Named Inventor	Lin et al.
		Art Unit	2874
(Multiple sheets used when necessary)		Examiner	Hoang Q. Tran
SHEET 1 OF 2		Attorney Docket No.	QCO.094A/061113

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number <i>Number - Kind Code (if known)</i> Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	4,863,245	9/5/1989	Roxlo	
	2	5,312,512	5/17/1994	Allman et al.	
	3	5,945,980	8/31/1999	Moissey et al.	
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	5	6,171,945	1/9/2001	Mandal et al.	
	6	6,275,220	8/14/2001	Nitta	
	7	6,288,824	9/11/2001	Kastalsky et al.	
	8	6,340,435	1/22/2002	Bjorkman et al.	
	9	6,424,094	7/23/2002	Feldman	
	10	6,449,084	9/10/2002	Guo	
	11	6,549,195	4/15/2003	Hikida et al.	
	12	6,660,656	12/9/2003	Cheung et al.	
	13	6,803,534	10/12/2004	Chen et al.	
	14	6,809,788	10/1/2004	Yamada et al.	
	15	6,947,200	9/20/2005	Huibers	
	16	7,323,217	1/29/2008	Lin et al.	
	17	2002-0070931	6/13/2002	Ishikawa	
	18	2002-0149850	10/17/2002	Heffner et al.	
	19	2002-0167072	11/14/2002	Andosca	
	20	2002-0171610	11/21/2002	Siwinski et al.	
	21	2002-0186209	12/12/2002	Cok	
	22	2003-0053078	3/20/2003	Missey et al.	
	23	2003-0118920	6/26/2003	Johnstone et al.	
	24	2003-0164350	9/4/2003	Hanson et al.	
	25	2004-0100594	5/27/2004	Huibers et al.	

Examiner Signature	Date Considered
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*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /HT/
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FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document <i>Country Code-Number-Kind Code</i> Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T ¹
	26	CH 680534	9/15/1992	Landis & GYR Betriebs AG		X-abstract
	27	EP 1 170 618	1/9/2002	Sony Corp		
	28	JP 2003195201	7/9/2003	Fuji Photo Film Co		X
	29	WO 03/046508	6/5/2003	Biomicroarrays		
	30	WO 04/000717	12/31/2003	Filtronic		
	31	WO 04/015741	2/19/2004	Unaxis USA		

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ¹
	32	Hall, Integrated optical interferometric detection method for micromachined capacitive acoustic transducers, App. Phy. Lett. 80:20(3859-3961) May 20, 2002	
	33	Matsumoto et al., Novel prevention method of stiction using silicon anodization for SOI structure, Sensors and Actuators, 72:2(153-159) January 19, 1999	
	34	Watanabe et al., Reduction of microtrenching and island formation in oxide plasma etching by employing electron beam charge neutralization, Applied Physics Letters, 79:17(2698-2700), October 22, 2001	

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Examiner Signature	/Hoang Tran/ (01/20/2009)	Date Considered
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